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Applicants : Hironori KOBAYASHI et al
For : RESIN COMPOSITION
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Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is a copy of the International Search Report, Form PTO-1449 and the references cited thereon. The references are listed in the specification and/or the relevance thereof is explained on the enclosed search report. Accordingly, further comment at this point in time should not be necessary.

Respectfully submitted,

TFC/smd


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Encl: Copy of International Search Report
Form PTO-1449 and one copy of each listed reference

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| INFORMATION DISCLOSURE CITATION | Applicant: Hironori KOBAYASHI et al |
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| | Group: Unknown Date: April 7, 2006 |

U.S. PATENT DOCUMENTS

| Examiner Initials* | Cite No. | Document Number - Kind Code | Publication Date MM-DD-YYYY | Name of Patentee or Applicant |
|--------------------|----------|-----------------------------|-----------------------------|-------------------------------|
| | AA | | | |
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FOREIGN PATENT DOCUMENTS

| Examiner Initials* | Cite No. | Country Code - Document Number - Kind Code | Publication Date MM-DD-YYYY | Name of Patentee or Applicant | Trans. |
|--------------------|----------|--|-----------------------------|-------------------------------|----------|
| | AE | JP 2003-206329 | 07-22-2003 | MASUDA et al | Abstract |
| | AF | JP 5-186479 | 07-27-1993 | OGINO et al | Abstract |
| | AG | JP 5-39295 | 02-19-1993 | TSUCHIDA et al | Abstract |
| | AH | JP 9-295992 | 11-18-1997 | TSUCHIDA et al | Abstract |
| | AI | JP 2000-297094 | 10-24-2000 | KUMAGAI | Abstract |
| | AJ | JP 2000-297093 | 10-24-2000 | KUMAGAI | Abstract |
| | AK | JP 11-92482 | 04-06-1999 | TSUCHIDA et al | Abstract |
| | AL | JP 2003-71378 | 03-11-2003 | KAGEISHI et al | Abstract |
| | AM | JP 11-310768 | 11-09-1999 | KOBAYASHI | Abstract |

NON PATENT LITERATURE DOCUMENTS

| Examiner Initials* | Cite No. | (Include Author, Title, Date, Pages, Etc.) |
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